

Notice of References CitedApplication/Control No.
09/891,885Applicant(s)/Patent Under
Reexamination
RAMSBEY ET AL.Examiner
Thomas J. MageeArt Unit
2811

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,238,975 B1	05-2001	Michael David Fliesler	438/258
	B	US-6,137,718	10-2000	Hans Reisinger	365/185.03
	C	US-5,378,649	01-1995	Heng S. Huang	437/52
	D	US-6,445,617 B1	09-2002	Kiyohiko Sakakibara	365/185.22
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Carlos H. Diaz, Thomas E. Kopley, and Paul J. Marcoux, "Building -in ESD/EOS Reliability for Sub-Halfmicron CMOS Processes," IEEE Trans. Electr. Devices, Vol. 43, (June, 1996) pp.991-999.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.